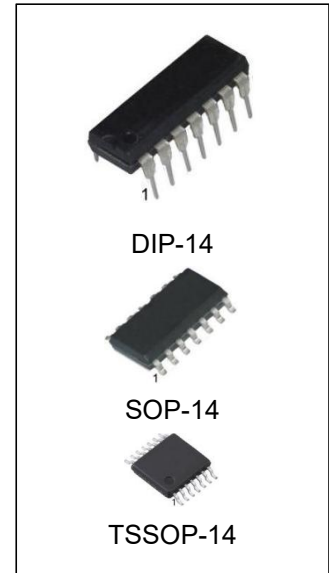


## CD4025B Triple 3-input Nor Gate

### Features:

- Wide supply voltage range from 3V to 15V
- Fully static operation
- 5V, 10V, and 15V parametric ratings
- Standardized symmetrical output characteristics
- Inputs and outputs are protected against electrostatic effects
- Specified from -40°C to +105°C
- Packaging information: DIP-14/SOP-14/TSSOP-14



### Ordering Information

DEVICE	Package Type	MARKING	Packing	Packing Qty
CD4025BN/HG	DIP-14	CD4025B	TUBE	1000pcs/box
CD4025BM/TR-HG	SOP-14	CD4025B	REEL	2500pcs/reel
CD4025BMT/TR-HG	TSSOP-14	CD4025B	REEL	2500pcs/reel

## General Description

The CD4025B is a triple 3-input NOR gate. The outputs are fully buffered for the highest noise immunity and pattern insensitivity to output impedance.

It operates over a recommended  $V_{DD}$  power supply range of 3V to 15V referenced to  $V_{SS}$  (usually ground). Unused inputs must be connected to  $V_{DD}$ ,  $V_{SS}$ , or another input.

## Block Diagram And Pin Description

### Block Diagram

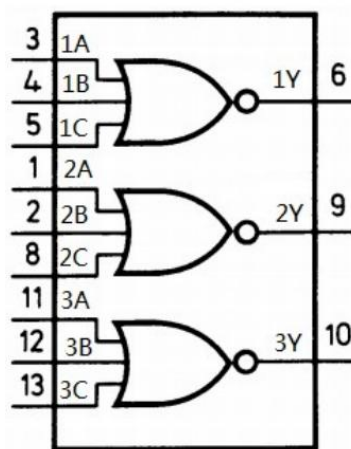


Figure 1. Functional diagram

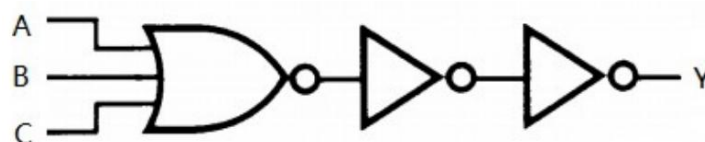
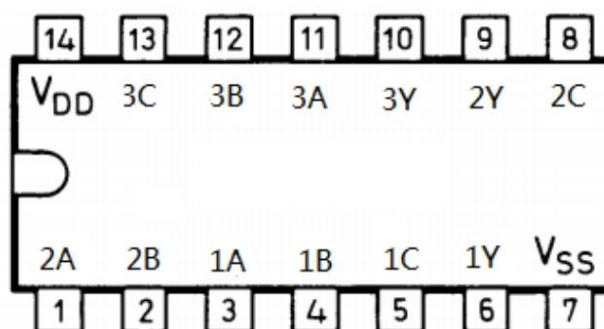


Figure 2. Logic diagram (one gate)

### Pin Configurations



DIP-14/SOP-14/TSSOP-14

## Pin Description

Pin No.	Pin Name	Description
1	2A	data input
2	2B	data input
3	1A	data input
4	1B	data input
5	1C	data input
6	1Y	data output
7	V <sub>SS</sub>	ground (0V)
8	2C	data input
9	2Y	data output
10	3Y	data output
11	3A	data input
12	3B	data input
13	3C	data input
14	V <sub>DD</sub>	supply voltage

## Function Table

Input			Output
nA	nB	nC	nY
L	L	L	H
H	X	X	L
X	H	X	L
X	X	H	L

**Note:** H=HIGH voltage level; L=LOW voltage level.

## Absolute Maximum Ratings

(Voltages are referenced to  $V_{SS}$  (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions	Min.	Max.	Unit
supply voltage	$V_{DD}$	-	-0.5	+18	V
DC input current	$I_{IK}$	any one input	-	$\pm 10$	mA
input voltage	$V_I$	all inputs	-0.5	$V_{DD}+0.5$	V
storage temperature	$T_{stg}$	-	-65	+150	°C
total power dissipation	$P_{tot}$	-	-	500	mW
device dissipation	P	per output transistor	-	100	mW
Soldering temperature	$T_L$	10s		260	°C

### Note:

- (1) Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is intended to be functional, but specific performance is not ensured.
- (2) For DIP-14 packages: above 70°C the value of  $P_{tot}$  derates linearly with 12mW/K.
- (3) For SOP-14 packages: above 70°C the value of  $P_{tot}$  derates linearly with 8mW/K.
- (4) For (T)SSOP-14 packages: above 60°C the value of  $P_{tot}$  derates linearly with 5.5mW/K.

## Recommended Operating Conditions

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
supply voltage	$V_{DD}$	-	3	-	15	V
Ambient temperature	$T_{amb}$	in free air	-40	-	+85	°C

## Electrical Characteristics

### DC Characteristics 1

( $T_{amb}=25^{\circ}\text{C}$ , voltages are referenced to  $V_{SS}$  (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions (V)			$T_{amb}=25^{\circ}\text{C}$			Unit
		$V_O$	$V_{IN}$	$V_{DD}$	Min.	Typ.	Max.	
supply current	$I_{DD}$	-	0, 5	5	-	0.01	0.25	$\mu\text{A}$
		-	0, 10	10	-	0.01	0.5	$\mu\text{A}$
		-	0, 15	15	-	0.01	1	$\mu\text{A}$
LOW-level output current	$I_{OL}$	0.4	0, 5	5	0.51	1	-	$\text{mA}$
		0.5	0, 10	10	1.3	2.6	-	$\text{mA}$
		1.5	0, 15	15	3.4	6.8	-	$\text{mA}$
HIGH-level output current	$I_{OH}$	4.6	0, 5	5	-0.51	-1	-	$\text{mA}$
		2.5	0, 5	5	-1.6	-3.2	-	$\text{mA}$
		9.5	0, 10	10	-1.3	-2.6	-	$\text{mA}$
		13.5	0, 15	15	-3.4	-6.8	-	$\text{mA}$
LOW-level output voltage	$V_{OL}$	-	0, 5	5	-	0	0.05	V
		-	0, 10	10	-	0	0.05	V
		-	0, 15	15	-	0	0.05	V
HIGH-level output voltage	$V_{OH}$	-	0, 5	5	4.95	5	-	V
		-	0, 10	10	9.95	10	-	V
		-	0, 15	15	14.95	15	-	V
LOW-level input voltage	$V_{IL}$	0.5, 4.5	-	5	-	-	1.5	V
		1, 9	-	10	-	-	3	V
		1.5, 13.5	-	15	-	-	4	V
HIGH-level input voltage	$V_{IH}$	0.5	-	5	3.5	-	-	V
		1	-	10	7	-	-	V
		1.5	-	15	11	-	-	V
input leakage current	$I_I$	-	0, 15	15	-	$\pm 10^{-5}$	$\pm 0.1$	$\mu\text{A}$

## DC Characteristics 2

( $T_{amb}=-40^{\circ}\text{C}$  to  $+85^{\circ}\text{C}$ , voltages are referenced to  $V_{SS}$  (ground=0V), unless otherwise specified.)

Parameter	Symbol	Conditions (V)			$T_{amb}=-40^{\circ}\text{C}$		$T_{amb}=+85^{\circ}\text{C}$		Unit
		$V_O$	$V_{IN}$	$V_{DD}$	Min.	Max.	Min.	Max.	
supply current	$I_{DD}$	-	0, 5	5	-	0.25	-	7.5	$\mu\text{A}$
		-	0, 10	10	-	0.5	-	15	$\mu\text{A}$
		-	0, 15	15	-	1	-	30	$\mu\text{A}$
LOW-level output current	$I_{OL}$	0.4	0, 5	5	0.61	-	0.42	-	mA
		0.5	0, 10	10	1.5	-	1.1	-	mA
		1.5	0, 15	15	4	-	2.8	-	mA
HIGH-level output current	$I_{OH}$	4.6	0, 5	5	-0.61	-	-0.42	-	mA
		2.5	0, 5	5	-1.8	-	-1.3	-	mA
		9.5	0, 10	10	-1.5	-	-1.1	-	mA
		13.5	0, 15	15	-4	-	-2.8	-	mA
LOW-level output voltage	$V_{OL}$	-	0, 5	5	-	0.05	-	0.05	V
		-	0, 10	10	-	0.05	-	0.05	V
		-	0, 15	15	-	0.05	-	0.05	V
HIGH-level output voltage	$V_{OH}$	-	0, 5	5	4.95	-	4.95	-	V
		-	0, 10	10	9.95	-	9.95	-	V
		-	0, 15	15	14.95	-	14.95	-	V
LOW-level input voltage	$V_{IL}$	0.5, 4.5	-	5	-	1.5	-	1.5	V
		1, 9	-	10	-	3	-	3	V
		1.5, 13.5	-	15	-	4	-	4	V
HIGH-level input voltage	$V_{IH}$	0.5	-	5	3.5	-	3.5	-	V
		1	-	10	7	-	7	-	V
		1.5	-	15	11	-	11	-	V
input leakage current	$I_I$	-	0, 15	15	-	$\pm 0.1$	-	$\pm 1$	$\mu\text{A}$

## AC Characteristics

( $T_{amb}=25^{\circ}\text{C}$ ,  $V_{SS}=0\text{V}$ ,  $t_r, t_f=20\text{ns}$ ,  $C_L=50\text{pF}$ ,  $R_L=200\text{k}\Omega$ , unless otherwise specified.)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
propagation delay time	$t_{PHL}, t_{PLH}$	$V_{DD}=5\text{V}$	-	125	250	ns
		$V_{DD}=10\text{V}$	-	60	120	ns
		$V_{DD}=15\text{V}$	-	45	90	ns
transition time	$t_{THL}, t_{TLH}$	$V_{DD}=5\text{V}$	-	100	200	ns
		$V_{DD}=10\text{V}$	-	50	100	ns
		$V_{DD}=15\text{V}$	-	40	80	ns
input capacitance	$C_i$	any input	-	5	7.5	pF

## Testing Circuit

### AC Testing Circuit

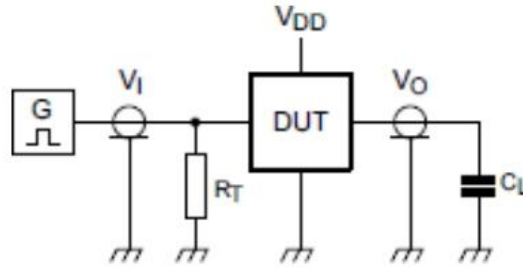


Figure 3. Test circuit for switching times

Definitions for test circuit:

DUT=Device Under Test.

$C_L$ =Load capacitance including jig and probe capacitance.

$R_T$ =Termination resistance should be equal to the output impedance  $Z_o$  of the pulse generator.

### AC Testing Waveforms

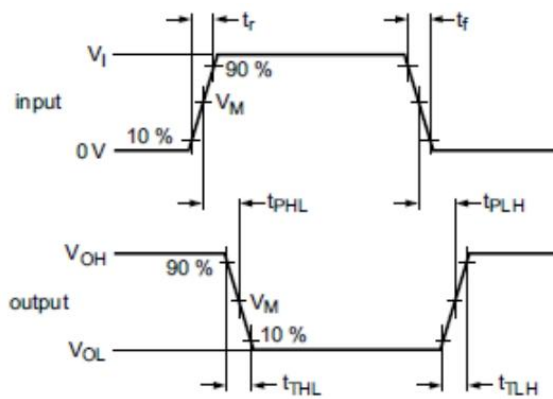


Figure 4. Propagation delay, output transition time

### Measurement Points

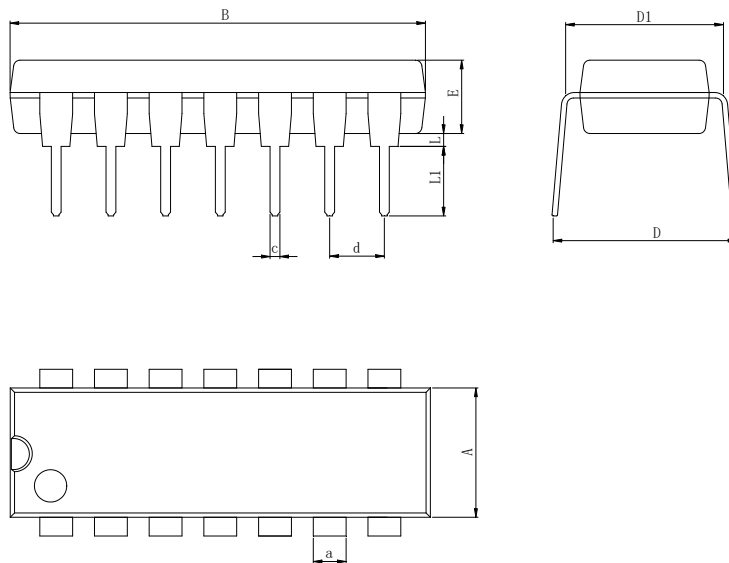
Supply voltage	Input	Output
$V_{DD}$	$V_M$	$V_M$
5V to 15V	$0.5 \times V_{DD}$	$0.5 \times V_{DD}$

### Test Data

Supply voltage	Input		Load
$V_{DD}$	$V_I$	$t_r, t_f$	$C_L$
5V to 15V	$V_{SS}$ or $V_{DD}$	$\leq 20\text{ns}$	50pF

## Physical Dimensions

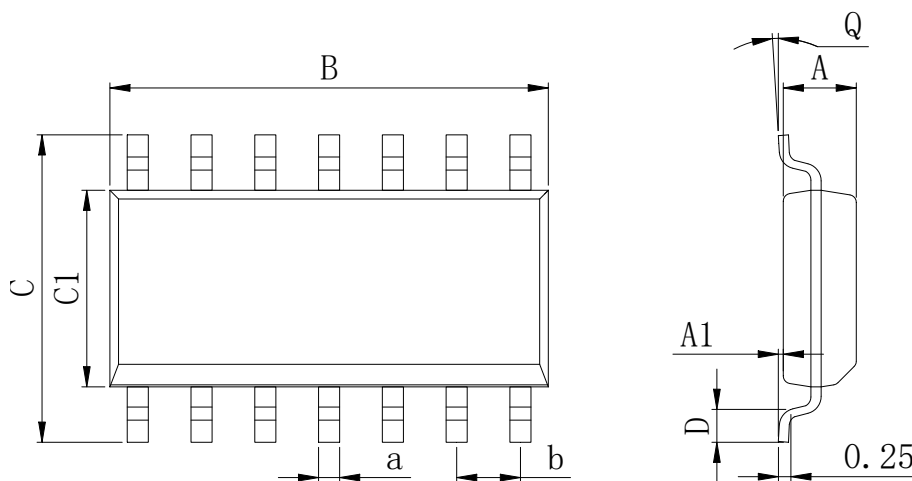
### DIP-14



**Dimensions In Millimeters(DIP-14)**

Symbol:	A	B	D	D1	E	L	L1	a	c	d
Min:	6.10	18.94	8.10	7.42	3.10	0.50	3.00	1.50	0.40	2.54 BSC
Max:	6.68	19.56	10.9	7.82	3.55	0.70	3.60	1.55	0.50	

### SOP-14

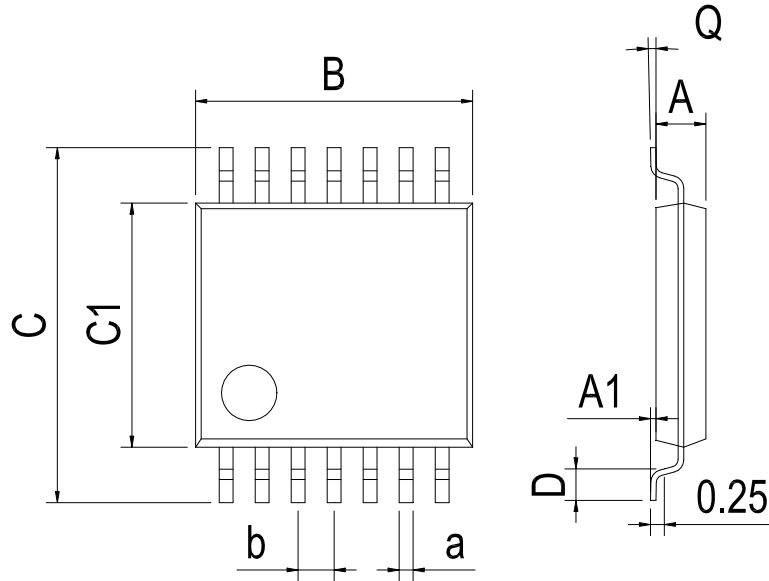


**Dimensions In Millimeters(SOP-14)**

Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	1.35	0.05	8.55	5.80	3.80	0.40	0°	0.35	1.27 BSC
Max:	1.55	0.20	8.75	6.20	4.00	0.80	8°	0.45	

**Physical Dimensions**

TSSOP-14



Dimensions In Millimeters(TSSOP-14)									
Symbol:	A	A1	B	C	C1	D	Q	a	b
Min:	0.85	0.05	4.90	6.20	4.30	0.40	0°	0.20	0.65 BSC
Max:	0.95	0.20	5.10	6.60	4.50	0.80	8°	0.25	

## Revision History

REVISION NUMBER	DATE	REVISION	PAGE
V1.0	2014-6	New	1-11
V1.1	2023-11	Document Reformatting、 Update DIP Package New Model	1-11、 1
V1.2	2024-10	Update Lead Temperature	4

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